Amendments to the Specification:

Please add the following new paragraph at line 1 of page 1:

CROSS-REFERENCE TO RELATED APPLICATIONS

This is a continuation of Application No. 10/219,599, filed August 14, 2000; which is a continuation of Application No. 09/626,420, filed July 26, 2000, now U.S. Patent No. 6,512,385, issued January 28, 2003; which claims the benefit of U.S. Provisional Patent Application Serial No. 60/145,617, filed July 26, 1999.

Please add the following new paragraphs after the paragraph ending on line 5 of page 8:

BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 is illustrates an electro-optic sampling technique.

FIG. 2 illustrates a voltage measurement system.

FIGS. 3A and 3B illustrate polarization changes.

FIG. 4 illustrates a holographic system.

FIGS. 5A and 5B illustrate holographic systems.

FIGS. 6A-6E illustrate crystal structures.

FIG. 7 illustrates a holographic apparatus.

FIG. 8 illustrates a holographic apparatus.

FIG. 9 illustrates transmission and reflection structures.

FIG. 10 illustrates an off-axis technique.

FIG. 11 illustrates an off-axis technique.

FIG. 12 illustrates a transmissive based system.

FIG. 13 illustrates an interferometric tester.

FIGS. 14A-C illustrates testers.

FIGS. 15A-15B illustrate testers.

FIG. 16 illustrates thermoplastic r cording.

FIG. 16A-16B illustrate interferograms.

FIG. 17 illustrate interference fringes.

FIG. 18 illustrate interference fringes.

FIG. 19 illustrate interference fringes.

FIG. 20 illustrate a recording structure.

FIG. 21 illustrate a recording structure.

FIG. 22 illustrate a recording structure.

FIG. 23 illustrate a recording structure.

FIG. 24 illustrate a recording structure.

FIG. 25 illustrate a recording structure.

FIG. 26A illustrate a recording structure.

FIG. 26B illustrate a recording structure.

FIG. 27A illustrate a recording structure.

FIG. 27B illustrate a recording structure.

FIG. 28 illustrate a testing apparatus.

FIG. 29 illustrates a photo-conductor.

FIG. 30 illustrates a barrier.

FIG. 31 illustrates a photo-conducting crystal.

FIG. 32 left blank.

FIG. 33 illustrates photo-currents.

FIG. 34 left blank.

FIG. 35 illustrates a testing apparatus.

FIG. 36 illustrates a testing apparatus.

FIGS. 37A-37B illustrate system components.

FIG. 38 illustrate illustrate a testing apparatus.

FIG. 39 illustrate interference patterns.

FIGS. 40A-40B illustrate interference patterns.

FIG. 40C illustrates a setup.

FIG. 41A-41B illustrates test output.

FIG 42 illustrate interference output.

FIG. 43 illustrate diffraction.

FIG. 44 illustrate a test setup.